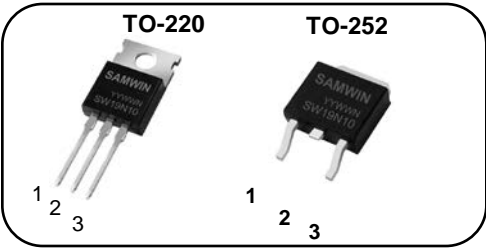


N-channel Enhanced mode TO-220/TO-252 MOSFET

Features

- High ruggedness
- Low  $R_{DS(ON)}$  (Typ 0.1Ω) @  $V_{GS}=10V$
- Low Gate Charge (Typ 15nC)
- Improved dv/dt Capability
- 100% Avalanche Tested
- Application: Synchronous Rectification, Li Battery Protect Board, Inverter



1. Gate 2. Drain 3. Source

**$BV_{DSS}$  : 100V**  
 **$I_D$  : 19A**  
 **$R_{DS(ON)}$  : 0.1Ω**

The circuit symbol for an N-channel MOSFET is shown. It consists of a circle with a horizontal line through it, representing the gate. The pins are labeled 1, 2, and 3. Pin 1 is the gate, pin 2 is the drain, and pin 3 is the source.

General Description

This power MOSFET is produced with advanced technology of SAMWIN. This technology enable the power MOSFET to have better characteristics, including fast switching time, low on resistance, low gate charge and especially excellent avalanche characteristics.



Order Codes

Item	Sales Type	Marking	Package	Packaging
1	SW P 19N10	SW19N10	TO-220	TUBE
2	SW D 19N10	SW19N10	TO-252	REEL

Absolute maximum ratings

Symbol	Parameter	Value		Unit
		TO-220	TO-252	
$V_{DSS}$	Drain to source voltage	100		V
$I_D$	Continuous drain current (@ $T_C=25^{\circ}C$ )	19*		A
	Continuous drain current (@ $T_C=100^{\circ}C$ )	11*		A
$I_{DM}$	Drain current pulsed (note 1)	68		A
$V_{GS}$	Gate to source voltage	$\pm 25$		V
$E_{AS}$	Single pulsed avalanche energy (note 2)	260		mJ
$E_{AR}$	Repetitive avalanche energy (note 1)	17		mJ
dv/dt	Peak diode recovery dv/dt (note 3)	15		V/ns
$P_D$	Total power dissipation (@ $T_C=25^{\circ}C$ )	208	118	W
	Derating factor above 25°C	1.66	0.94	W/°C
$T_{STG}, T_J$	Operating junction temperature & storage temperature	-55 ~ + 150		°C
$T_L$	Maximum lead temperature for soldering purpose, 1/8 from case for 5 seconds.	300		°C

\*. Drain current is limited by junction temperature.

Thermal characteristics

Symbol	Parameter	Value		Unit
		TO-220	TO-252	
$R_{thjc}$	Thermal resistance, Junction to case	0.6	1.06	°C/W
$R_{thja}$	Thermal resistance, Junction to ambient	62.5		°C/W

Electrical characteristic (  $T_C = 25^\circ\text{C}$  unless otherwise specified )

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
<b>Off characteristics</b>						
$BV_{DSS}$	Drain to source breakdown voltage	$V_{GS}=0V, I_D=250\mu A$	100			V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown voltage temperature coefficient	$I_D=250\mu A$ , referenced to $25^\circ\text{C}$		0.093		$V/^\circ\text{C}$
$I_{DSS}$	Drain to source leakage current	$V_{DS}=100V, V_{GS}=0V$			1	$\mu A$
		$V_{DS}=80V, T_C=125^\circ\text{C}$			100	$\mu A$
$I_{GSS}$	Gate to source leakage current, forward	$V_{GS}=20V, V_{DS}=0V$			100	nA
	Gate to source leakage current, reverse	$V_{GS}=-20V, V_{DS}=0V$			-100	nA
<b>On characteristics</b>						
$V_{GS(TH)}$	Gate threshold voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	2.0		4.0	V
$R_{DS(ON)}$	Drain to source on state resistance	$V_{GS}=10V, I_D=9.5A$		0.1	0.12	$\Omega$
$G_{fs}$	Forward transconductance	$V_{DS}=40V, I_D=9.5A$		3.2		S
<b>Dynamic characteristics</b>						
$C_{iss}$	Input capacitance	$V_{GS}=0V, V_{DS}=25V, f=1\text{MHz}$		600		pF
$C_{oss}$	Output capacitance			165		
$C_{rss}$	Reverse transfer capacitance			32		
$t_{d(on)}$	Turn on delay time	$V_{DS}=50V, I_D=19A, V_{GS}=10V, R_G=25\Omega$ (note 4,5)		10		ns
$t_r$	Rising time			40		
$t_{d(off)}$	Turn off delay time			28		
$t_f$	Fall time			15		
$Q_g$	Total gate charge	$V_{DS}=80V, V_{GS}=10V, I_D=19A$ (note 4,5)		15		nC
$Q_{gs}$	Gate-source charge			4		
$Q_{gd}$	Gate-drain charge			6.5		

## Source to drain diode ratings characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_S$	Continuous source current	Integral reverse p-n Junction diode in the MOSFET			19	A
$I_{SM}$	Pulsed source current				62.4	A
$V_{SD}$	Diode forward voltage drop.	$I_S=19A, V_{GS}=0V$			1.4	V
$t_{rr}$	Reverse recovery time	$I_S=19A, V_{GS}=0V, di/dt=100A/\mu s$		52		ns
$Q_{rr}$	Reverse recovery charge			128		nC

※. Notes

1. Repeitative rating : pulse width limited by junction temperature.
2.  $L = 1.4\text{mH}, I_{AS} = 19A, V_{DD} = 25V, R_G=25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 19A, di/dt = 100A/\mu s, V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse Width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$ .
5. Essentially independent of operating temperature.

Fig. 1. On-state characteristics

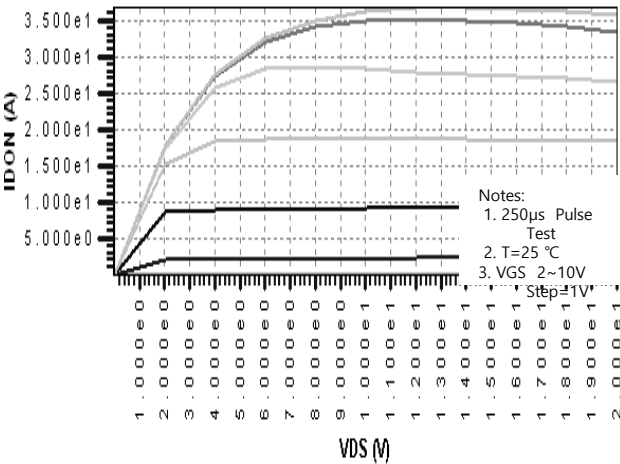


Fig. 2. Gate charge characteristics

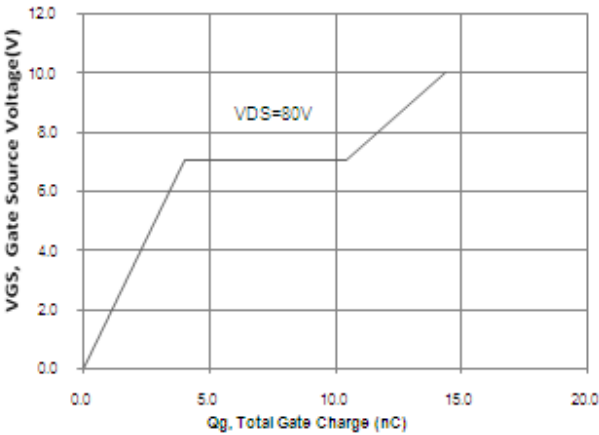


Fig. 3. On state current vs. diode forward voltage

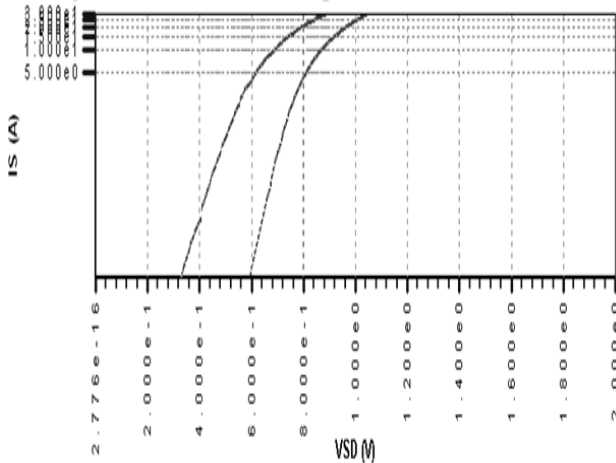


Fig 4. Breakdown Voltage Variation vs. Junction Temperature

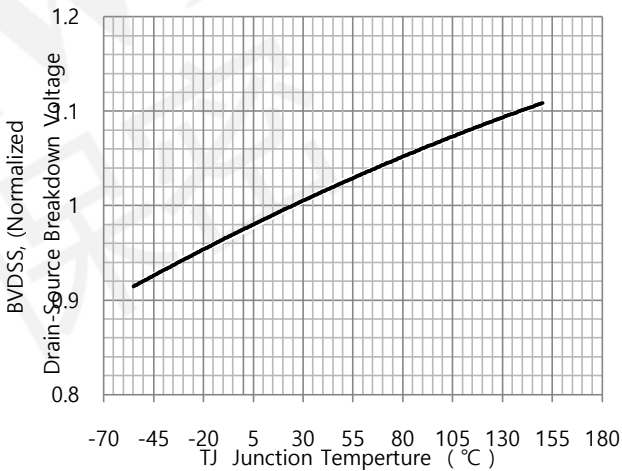


Fig. 5. On resistance variation vs. junction temperature

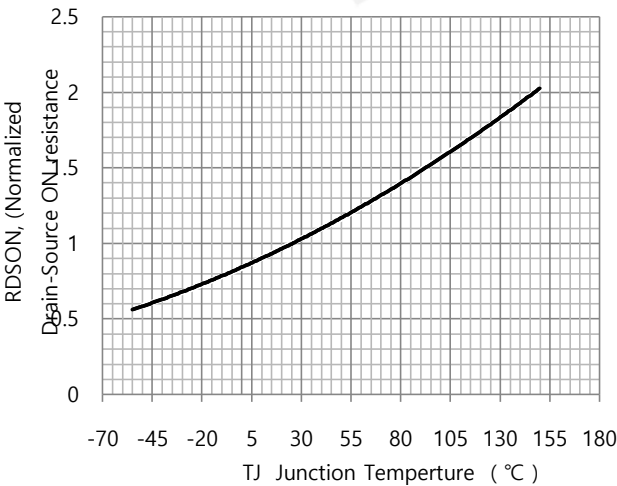


Fig. 6. Maximum safe operating area

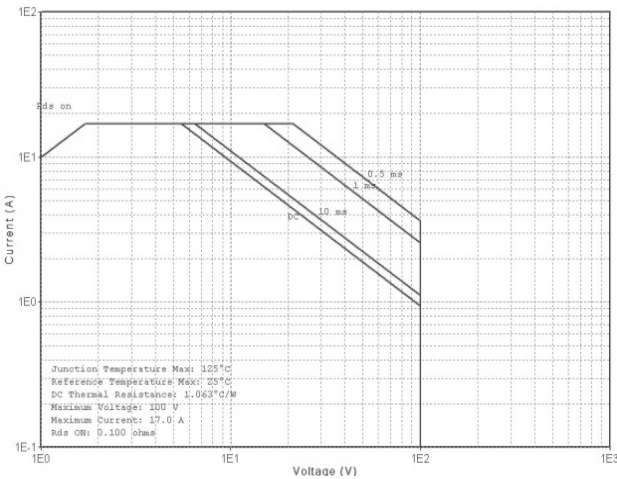


Fig. 7. Transient thermal response curve

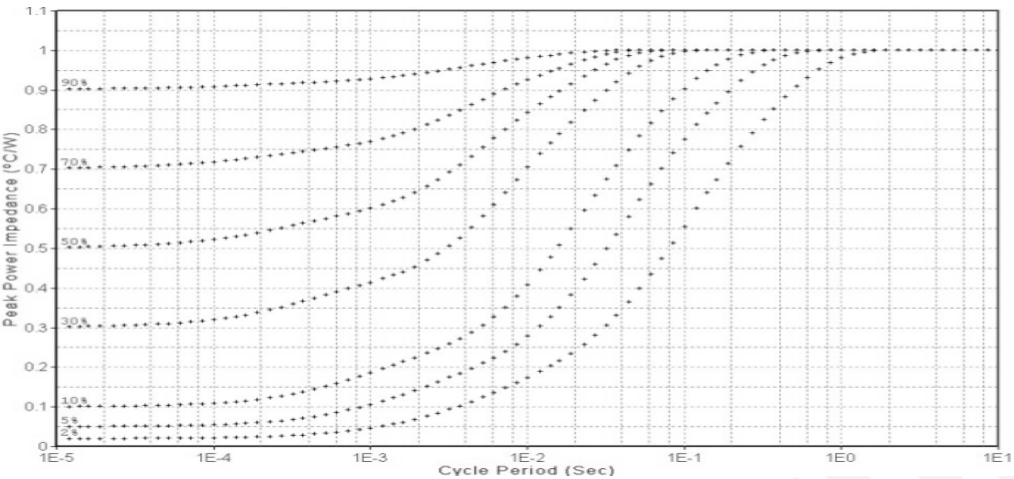


Fig. 8. Gate charge test circuit & waveform

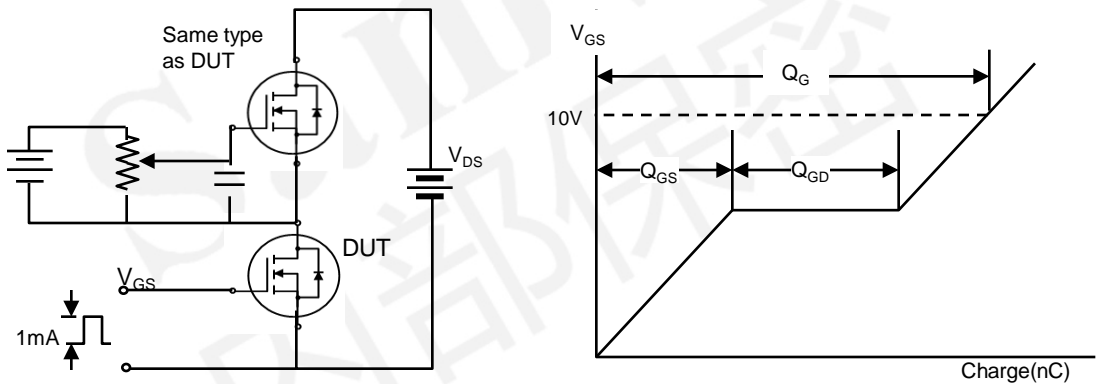


Fig. 9. Switching time test circuit & waveform

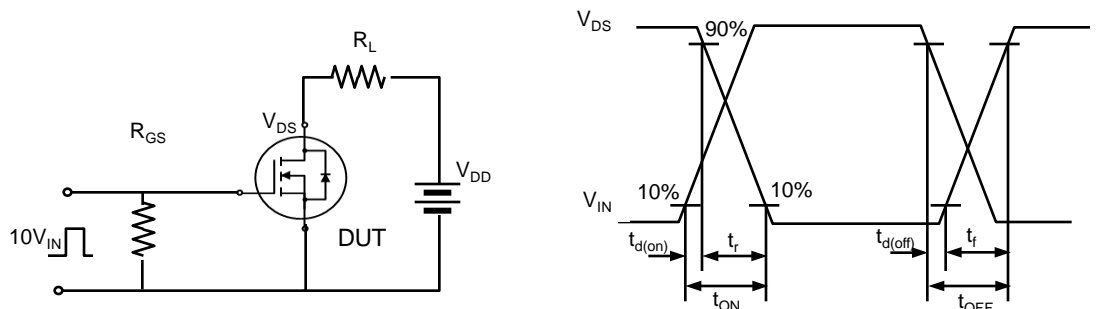


Fig. 10. Unclamped Inductive switching test circuit & waveform

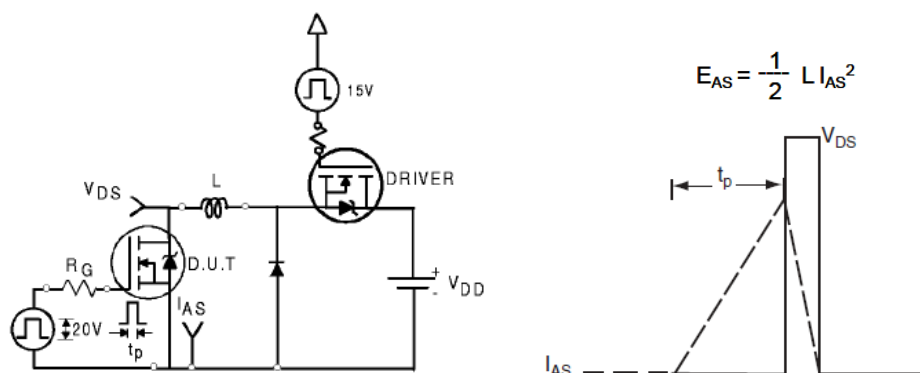
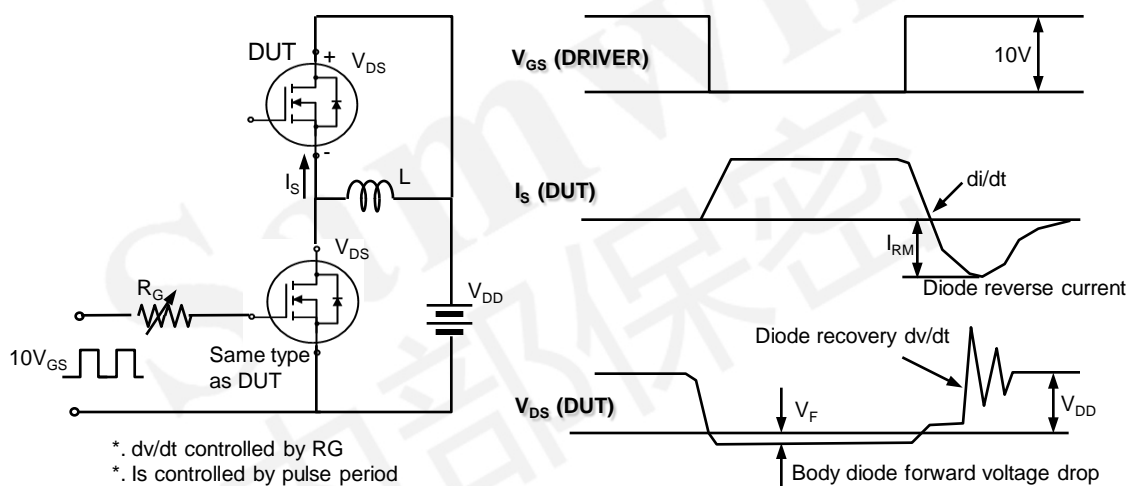



Fig. 11. Peak diode recovery dv/dt test circuit & waveform



## DISCLAIMER

- \* All the data & curve in this document was tested in XI'AN SEMIPOWER TESTING & APPLICATION CENTER.
- \* This product has passed the PCT,TC,HTRB,HTGB,HAST,PC and Solderdunk reliability testing.
- \* Qualification standards can also be found on the Web site (<http://www.semipower.com.cn>) 
- \* Suggestions for improvement are appreciated, Please send your suggestions to [samwin@samwinsemi.com](mailto:samwin@samwinsemi.com)